Machine Learning in Image Analysis and Pattern Recognition

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Message from the Guest Editors

Images are ubiqutous. Tens of millions of images are captured everyday for a variety of applications in almost all domains of human endeavors. We have come to rely on machine learning, including deep learning, to analyze and extract actionable information from captured images via recgnizing the presence of patterns of interests. In recent years, these methods, particularly those using deep learning, have exhibited performance levels surpassing human performance in certain applications.

The purpose of this Special Issue is to chart the progress in applying machine learning, including deep learning, to a broad range of image analysis and pattern recognition problems and applications. To this end, we invite original research articles making unique contributions to the theory, methodology, and applications of machine learning in image analysis and pattern recognition. We also welcome comprehensive survey articles dealing with any particular aspect of machine learning vis-à-vis image analysis and pattern recognition.

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Special Issue

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Message from the Editor-in-Chief

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